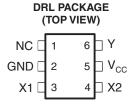
# SN74LVC1GX04-EP CRYSTAL OSCILLATOR DRIVER

SGDS029-SEPTEMBER 2007

### **FEATURES**

- Controlled Baseline
  - One Assembly
  - One Test Site
  - One Fabrication Site
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product-Change Notification
- Qualification Pedigree (1)
- Available in Texas Instruments NanoStar<sup>™</sup> and NanoFree<sup>™</sup> Packages
- Supports 5-V V<sub>CC</sub> Operation
- Inputs Accept Voltages to 5.5 V
- One Unbuffered Inverter (SN74LVC1GU04) and One Buffered Inverter (SN74LVC1G04)
- Suitable for Commonly Used Clock Frequencies:
  - 15 kHz, 3.58 MHz, 4.43 MHz, 13 MHz,
     25 MHz, 26 MHz, 27 MHz, 28 MHz
- Max t<sub>pd</sub> of 3.7 ns at 3.3 V
- (1) Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

- Low Power Consumption, 10 μA Max I<sub>CC</sub>
- ±24 mA Output Drive at 3.3 V
- I<sub>off</sub> Supports Partial-Power-Down Mode Operation
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)



See mechanical drawings for dimensions. NC – No internal connection

### **DESCRIPTION/ORDERING INFORMATION**

The SN74LVC1GX04 is designed for 1.65-V to 5.5-V V<sub>CC</sub> operation. This device incorporates the SN74LVC1GU04 (inverter with unbuffered output) and the SN74LVC1G04 (inverter) functions into a single device. The LVC1GX04 is optimized for use in crystal oscillator applications.

## ORDERING INFORMATION(1)

T <sub>A</sub>	PACKAGE <sup>(2)</sup>		ORDERABLE PART NUMBER	TOP-SIDE MARKING (3)
-55°C to 125°C	SOT (SOT-553) – DRL	Reel of 4000	CLVC1GX04MDRLREP	CDD

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.
- (2) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.
- (3) DRL: The actual top-side marking has one additional character that designates the assembly/test site.

M

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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# **DESCRIPTION/ORDERING INFORMATION (CONTINUED)**

X1 and X2 can be connected to a crystal or resonator in oscillator applications. The device provides an additional buffered inverter (Y) for signal conditioning (see Figure 3). The additional buffered inverter improves the signal quality of the crystal oscillator output by making it rail to rail.

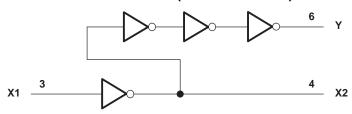
NanoStar<sup>™</sup> and NanoFree<sup>™</sup> package technology is a major breakthrough in IC packaging concepts, using the die as the package.

This device is fully specified for partial-power-down applications using  $I_{off}$  (Y output only). The  $I_{off}$  circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

#### **FUNCTION TABLE**

INPUT	OUTI	PUTS
X1	X2	Υ
Н	L	Н
L	Н	L

### **LOGIC DIAGRAM (POSITIVE LOGIC)**



# Absolute Maximum Ratings<sup>(1)</sup>

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
$V_{CC}$	Supply voltage range	-0.5	6.5	V	
$V_{I}$	Input voltage range (2)		-0.5	6.5	V
Vo	Voltage range applied to Y output in the high-imp	pedance or power-off state (2)	-0.5	6.5	V
Vo	Voltage range applied to any output in the high o	Voltage range applied to any output in the high or low state (2)(3)			
I <sub>IK</sub>	Input clamp current	V <sub>I</sub> < 0		-50	mA
I <sub>OK</sub>	Output clamp current	V <sub>O</sub> < 0		-50	mA
Io	Continuous output current			±50	mA
	Continuous current through V <sub>CC</sub> or GND		±100	mA	
$\theta_{JA}$	Package thermal impedance (4)		142	°C/W	
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

<sup>(2)</sup> The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>(3)</sup> The value of V<sub>CC</sub> is provided in the recommended operating conditions table.

<sup>(4)</sup> The package thermal impedance is calculated in accordance with JESD 51-7.





# Recommended Operating Conditions<sup>(1)</sup>

			MIN	MAX	UNIT	
		Operating	1.65	5.5		
$V_{CC}$	Supply voltage	Data retention only	1.5		V	
		Crystal oscillator use	2			
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 1.65 V to 5.5 V	$0.75 \times V_{CC}$		V	
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 1.65 V to 5.5 V		$0.25 \times V_{CC}$	V	
$V_{I}$	Input voltage		0	5.5	V	
.,	Outrot valta a	X2, Y	0	V <sub>CC</sub>	V	
Vo	Output voltage	Y output only, Power-down mode, $V_{CC} = 0 \text{ V}$	0	5.5	V	
		V <sub>CC</sub> = 1.65 V		-4		
	High-level output current	V <sub>CC</sub> = 2.3 V		-8		
$I_{OH}$		V 0 V		-16	mA	
		V <sub>CC</sub> = 3 V		-24		
		V <sub>CC</sub> = 4.5 V		-32		
		V <sub>CC</sub> = 1.65 V		4		
		V <sub>CC</sub> = 2.3 V		8		
$I_{OL}$	Low-level output current	V 0 V		16	mA	
		V <sub>CC</sub> = 3 V		24		
		V <sub>CC</sub> = 4.5 V		32		
		$V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}, 2.5 \text{ V} \pm 0.2 \text{ V}$		20		
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$			ns/V	
		$V_{CC} = 5 \text{ V } \pm 0.5 \text{ V}$		10		
T <sub>A</sub>	Operating free-air temperature		-55	125	°C	

<sup>(1)</sup> All unused inputs of the device must be held at  $V_{CC}$  or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

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### **Electrical Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

P	ARAMETER	TEST	CONDITIONS	V <sub>CC</sub>	MIN TYP	<sup>(1)</sup> MAX	UNIT	
		$I_{OH} = -100 \ \mu A$		1.65 V to 5.5 V	V <sub>CC</sub> - 0.1			
		$I_{OH} = -4 \text{ mA}$		1.65 V	1.2			
.,		$I_{OH} = -8 \text{ mA}$	V - F F V or CND	2.3 V	1.9			
V <sub>OH</sub>	I <sub>OH</sub> = -16 mA		V <sub>I</sub> = 5.5 V or GND	3 V	2.4		V	
		$I_{OH} = -24 \text{ mA}$		3 V	2.3			
		$I_{OH} = -32 \text{ mA}$		4.5 V	3.8			
		I <sub>OL</sub> = 100 μA		1.65 V to 5.5 V		0.1		
		I <sub>OL</sub> = 4 mA		1.65 V			0.45	
\/		$I_{OL} = 8 \text{ mA}$	V <sub>I</sub> = 5.5 V or GND	2.3 V			3 V	
V <sub>OL</sub>	I <sub>OL</sub> = 16 mA		V <sub>1</sub> = 5.5 V OI GND	3 V	0.4		V	
		I <sub>OL</sub> = 24 mA		3 V		0.63		
		I <sub>OL</sub> = 32 mA		4.5 V		0.70		
I	X1	V <sub>I</sub> = 5.5 V or GND		0 to 5.5 V		±5	μA	
I <sub>off</sub>	X1, Y	$V_I$ or $V_O = 5.5 \text{ V}$		0		±10	μA	
Icc		V <sub>I</sub> = 5.5 V or GND,	I <sub>O</sub> = 0	1.65 V to 5.5 V	V 10		μΑ	
Ci		$V_I = V_{CC}$ or GND		3.3 V		7	pF	

<sup>(1)</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C.

## **Switching Characteristics**

over recommended operating free-air temperature range,  $C_L = 30 \text{ pF}$  or 50 pF (unless otherwise noted) (see Figure 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = ± 0.		V <sub>CC</sub> = ± 0.		UNIT
	(INPUT)	(001701)	MIN	MAX	MIN	MAX	
4	X1	X2	0.8	3.7	0.8	3.2	20
<sup>L</sup> pd	ΧI	Y <sup>(1)</sup>	2	7.8	2	5	ns

<sup>(1)</sup> X2 - no external load

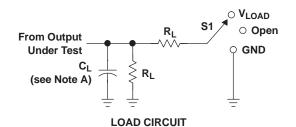
# **Operating Characteristics**

 $T_A = 25^{\circ}C$ 

	PARAMETER	TEST	V <sub>CC</sub> = 3.3 V	V <sub>CC</sub> = 5 V	UNIT
TAKAMETEK		CONDITIONS	TYP	TYP	0
$C_{pd}$	Power dissipation capacitance	f = 10 MHz	24	35	pF

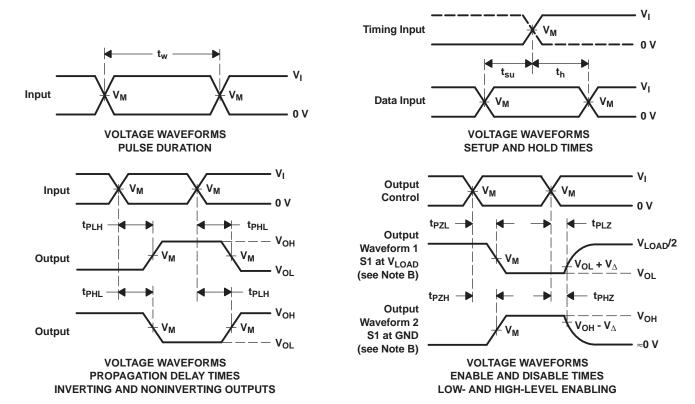


### PARAMETER MEASUREMENT INFORMATION



TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	V <sub>LOAD</sub>
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

.,	INF	PUTS	.,	.,	_	-	.,
V <sub>CC</sub>	V <sub>I</sub> t <sub>r</sub> /t <sub>f</sub>		V <sub>M</sub>	V <sub>LOAD</sub>	C <sub>L</sub>	R <sub>L</sub>	$oldsymbol{V}_{\Delta}$
1.8 V $\pm$ 0.15 V	V <sub>CC</sub>	≤2 ns	V <sub>CC</sub> /2	2×V <sub>CC</sub>	15 pF	<b>1 M</b> Ω	0.15 V
2.5 V $\pm$ 0.2 V	$V_{CC}$	≤2 ns	V <sub>CC</sub> /2	2×V <sub>CC</sub>	15 pF	<b>1 M</b> Ω	0.15 V
3.3 V $\pm$ 0.3 V	3 V	≤2.5 ns	1.5 V	6 V	15 pF	<b>1 M</b> Ω	0.3 V
5 V $\pm$ 0.5 V	Vcc	≤2.5 ns	V <sub>CC</sub> /2	2×V <sub>CC</sub>	15 pF	<b>1 M</b> Ω	0.3 V



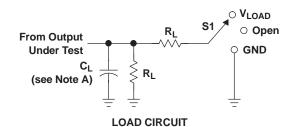
NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ .
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t<sub>PLZ</sub> and t<sub>PHZ</sub> are the same as t<sub>dis</sub>.
- F. t<sub>PZL</sub> and t<sub>PZH</sub> are the same as t<sub>en</sub>.
- G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .
- H. All parameters and waveforms are not applicable to all devices.

Figure 1. Load Circuit and Voltage Waveforms

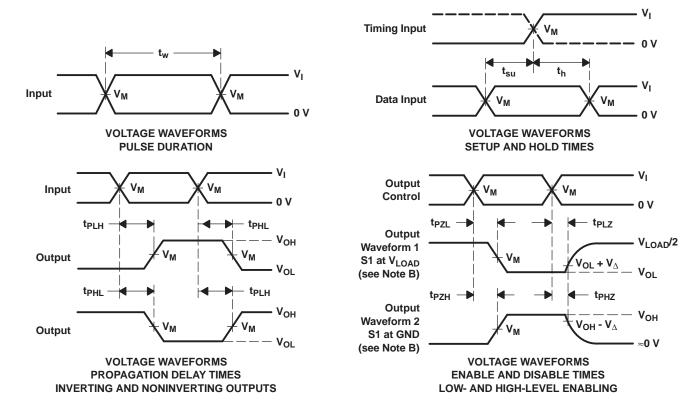


### PARAMETER MEASUREMENT INFORMATION



TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	$V_{LOAD}$
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

V	INI	PUTS		V		Б	V
V <sub>CC</sub>	VI	t <sub>r</sub> /t <sub>f</sub>	V <sub>M</sub>	V <sub>LOAD</sub>	CL	R <sub>L</sub>	$oldsymbol{V}_{\Delta}$
1.8 V $\pm$ 0.15 V	V <sub>CC</sub> ≤2 ns		V <sub>CC</sub> /2	2×V <sub>CC</sub>	30 pF	<b>1 k</b> Ω	0.15 V
2.5 V $\pm$ 0.2 V	V <sub>CC</sub>	≤2 ns	V <sub>CC</sub> /2	2×V <sub>CC</sub>	30 pF	500 Ω	0.15 V
3.3 V $\pm$ 0.3 V	3 V	≤2.5 ns	1.5 V	6 V	50 pF	500 Ω	0.3 V
5 V $\pm$ 0.5 V	V <sub>CC</sub>	≤2.5 ns	V <sub>CC</sub> /2	2×V <sub>CC</sub>	50 pF	500 Ω	0.3 V



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ .
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t<sub>PLZ</sub> and t<sub>PHZ</sub> are the same as t<sub>dis</sub>.
- F. t<sub>PZL</sub> and t<sub>PZH</sub> are the same as t<sub>en</sub>.
- G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .
- H. All parameters and waveforms are not applicable to all devices.

Figure 2. Load Circuit and Voltage Waveforms

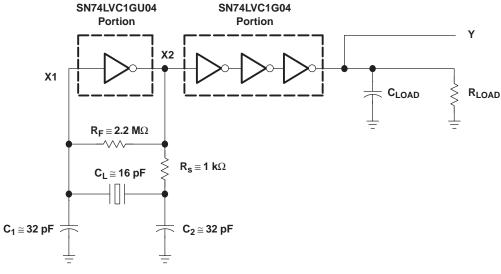


### APPLICATION INFORMATION

Figure 3 shows a typical application of the SN74LVC1GX04 in a Pierce oscillator circuit. The buffered inverter (SN74LVC1G04 portion) produces a rail-to-rail voltage waveform. The recommended load for the crystal shown in this example is 16 pF. The value of the recommended load (C<sub>I</sub>) can be found in the crystal manufacturer's data sheet.

Values of  $C_1$  and  $C_2$  are chosen so that  $C_L = \frac{C_1 C_2}{C_1 + C_2}$  and  $C_1 \equiv C_2$ .  $R_s$  is the current-limiting resistor, and the value depends on the maximum power dissipation of the crystal. Generally, the recommended value of  $R_s$  is specified in the crystal manufacturer's data sheet and, usually, this value is approximately equal to the reactance

 $R_S = X_C$  of  $C_2$  at resonance frequency, i.e.,  $C_2 = X_C$  of operation. Usually, the value is chosen to be within 1 M $\Omega$  to 10 M $\Omega$ .

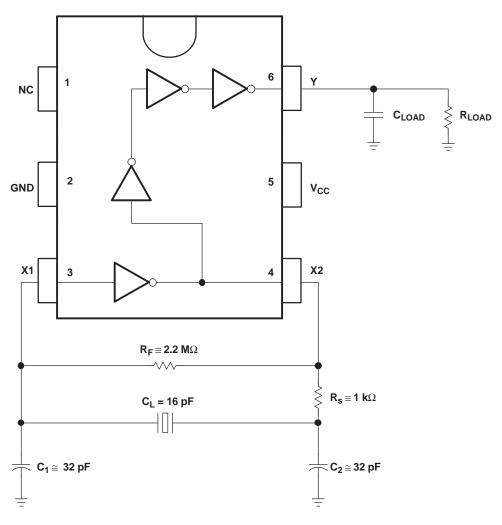


a) Logic Diagram View

Figure 3. Oscillator Circuit



### **APPLICATION INFORMATION**



b) Oscillator Circuit in DBV or DCK Pinout

Figure 3. Oscillator Circuit (continued)

## **Practical Design Tips**

- The open-loop gain of the unbuffered inverter decreases as power-supply voltage decreases. This decreases
  the closed-loop gain of the oscillator circuit. The value of R<sub>s</sub> can be decreased to increase the closed-loop
  gain, while maintaining the power dissipation of the crystal within the maximum limit.
- R<sub>s</sub> and C<sub>2</sub> form a low-pass filter and reduce spurious oscillations. Component values can be adjusted, based on the desired cutoff frequency.
- C<sub>2</sub> can be increased over C<sub>1</sub> to increase the phase shift and help in start-up of the oscillator. Increasing C<sub>2</sub> may affect the duty cycle of the output voltage.
- At high frequency, phase shift due to R<sub>s</sub> becomes significant. In this case, R<sub>s</sub> can be replaced by a capacitor to reduce the phase shift.

# SN74LVC1GX04-EP CRYSTAL OSCILLATOR DRIVER

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### **APPLICATION INFORMATION**

## **Testing**

After the selection of proper component values, the oscillator circuit should be tested using these components. To ensure that the oscillator circuit performs within the recommended operating conditions, follow these steps:

- 1. Without a crystal, the oscillator circuit should not oscillate. To check this, the crystal can be replaced by its equivalent parallel-resonant resistance.
- 2. When the power-supply voltage drops, the closed-loop gain of the oscillator circuit reduces. Ensure that the circuit oscillates at the appropriate frequency at the lowest  $V_{CC}$  and highest  $V_{CC}$ .
- 3. Ensure that the duty cycle, start-up time, and frequency drift over time is within the system requirements.

Submit Documentation Feedback

9



## PACKAGE OPTION ADDENDUM

10-Dec-2020

### PACKAGING INFORMATION

www.ti.com

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CLVC1GX04MDRLREP	ACTIVE	SOT-5X3	DRL	6	4000	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-55 to 125	CDD	Samples
V62/07632-01XE	ACTIVE	SOT-5X3	DRL	6	4000	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-55 to 125	CDD	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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# **PACKAGE OPTION ADDENDUM**

10-Dec-2020

#### OTHER QUALIFIED VERSIONS OF SN74LVC1GX04-EP:

● Catalog: SN74LVC1GX04

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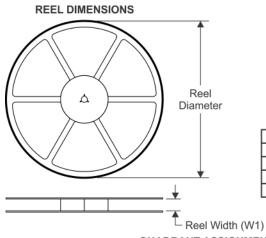
NOTE: Qualified Version Definitions:

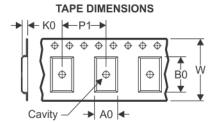
• Catalog - TI's standard catalog product

# PACKAGE MATERIALS INFORMATION

www.ti.com 3-Aug-2017

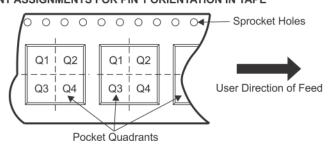
## TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

# QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

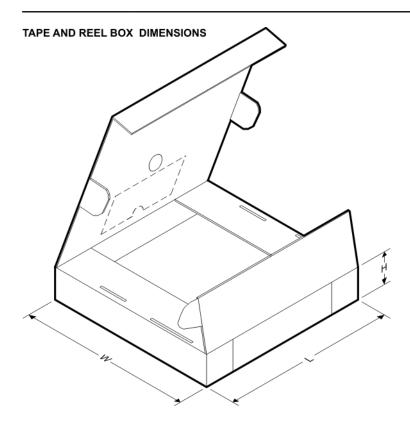


### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CLVC1GX04MDRLREP	SOT-5X3	DRL	6	4000	180.0	8.4	1.98	1.78	0.69	4.0	8.0	Q3

**PACKAGE MATERIALS INFORMATION** 

www.ti.com 3-Aug-2017

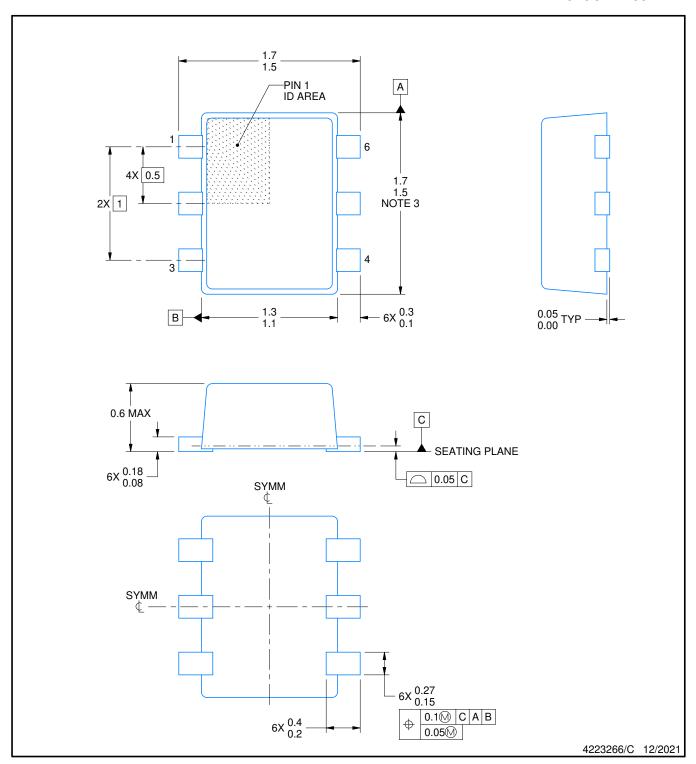


### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
CLVC1GX04MDRLREP	SOT-5X3	DRL	6	4000	202.0	201.0	28.0	



PLASTIC SMALL OUTLINE

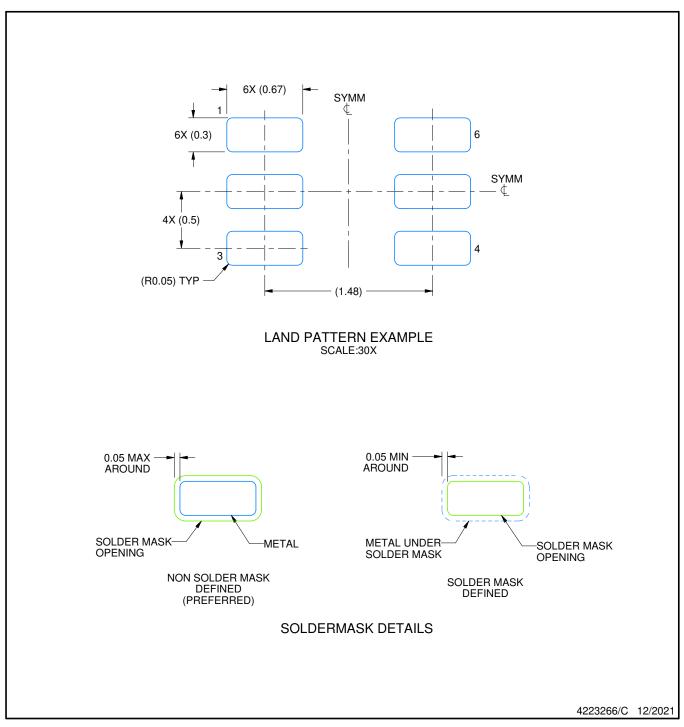


## NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
   This drawing is subject to change without notice.
   This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
  4. Reference JEDEC registration MO-293 Variation UAAD



PLASTIC SMALL OUTLINE



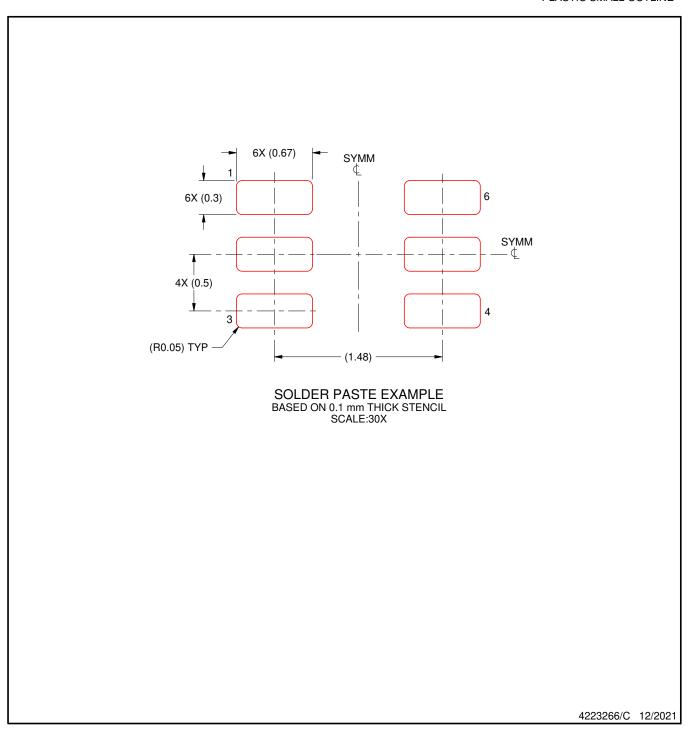
NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
7. Land pattern design aligns to IPC-610, Bottom Termination Component (BTC) solder joint inspection criteria.



PLASTIC SMALL OUTLINE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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